

<b>Notice of References Cited</b>	Application/Control No. 10/581,578	Applicant(s)/Patent Under Reexamination HAYASHI ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0179537 A1	09-2003	Tanaka et al.	361/502
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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